

# A Criterion for a Sufficiently Large Dither Amplitude to Mitigate Non-linear Glitches

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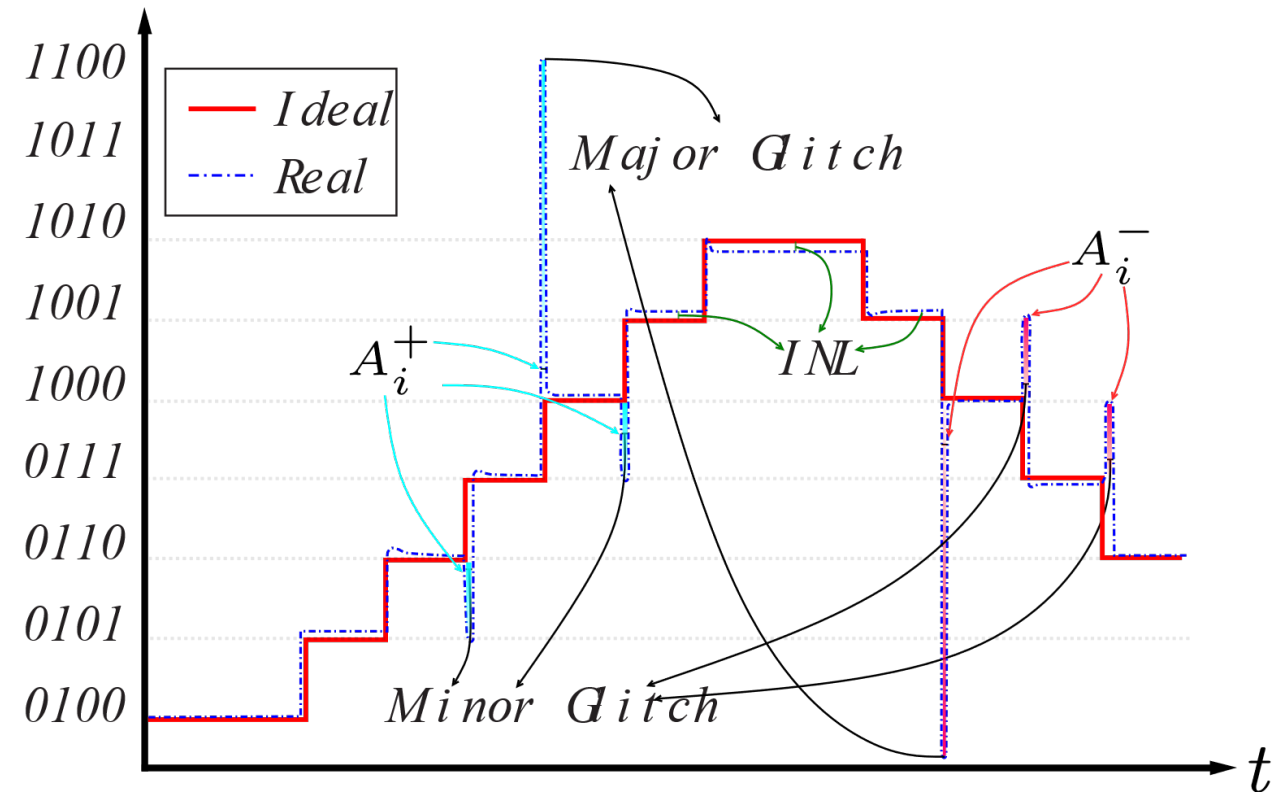
Co-supervisor: John-Josef Leth (AAU)



# GLITCHED DISTURBANCES

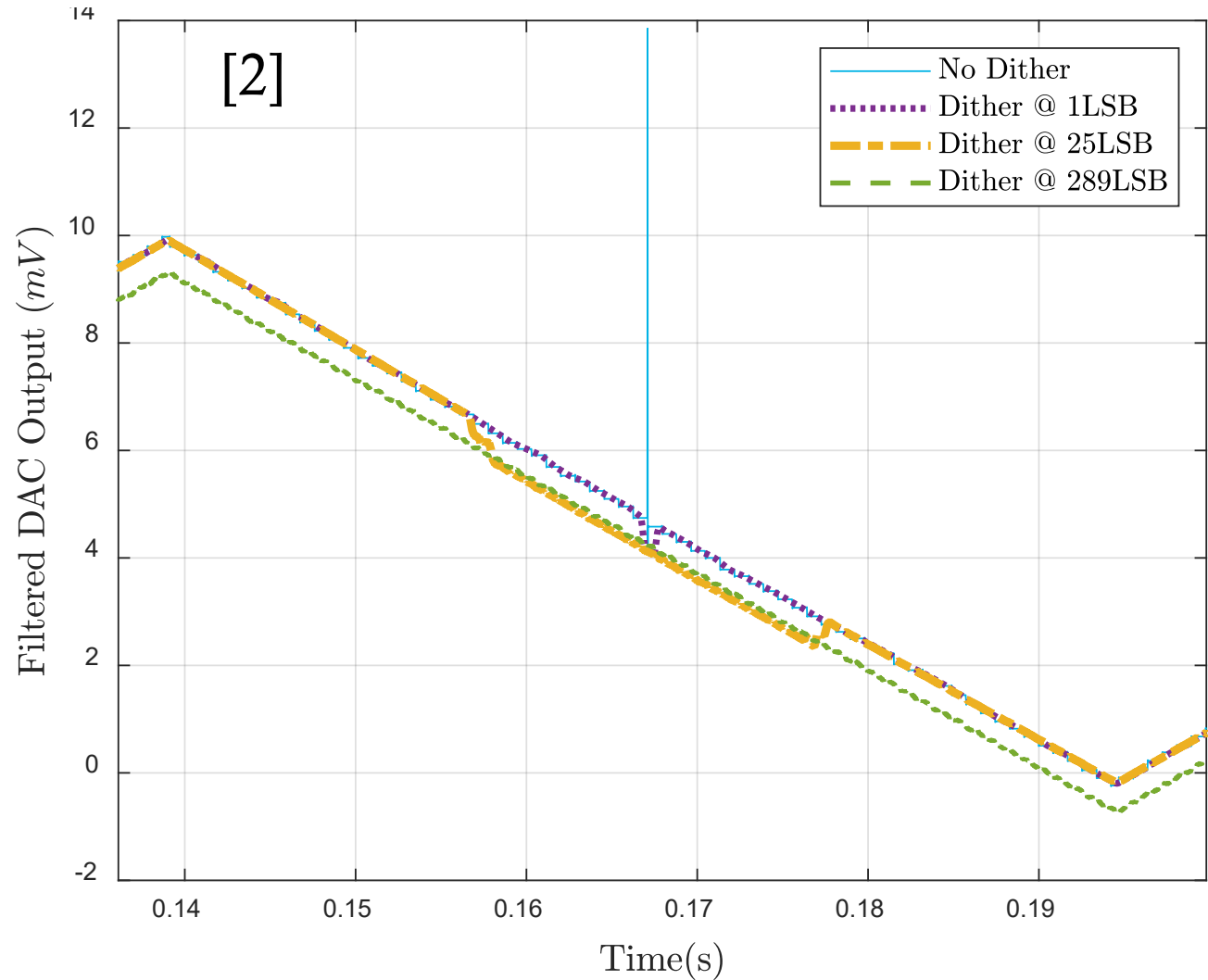
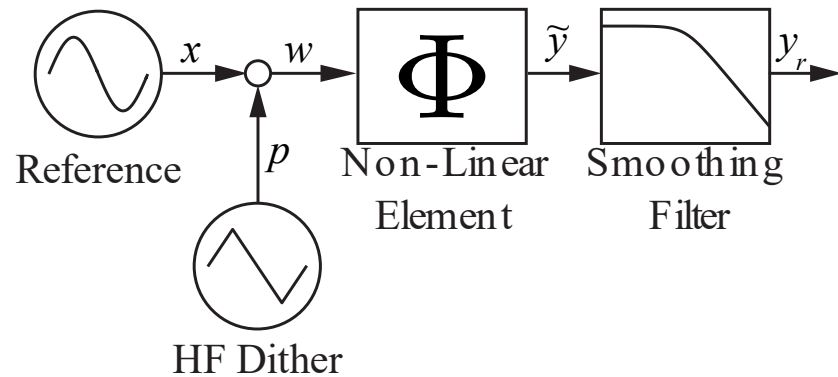
- Glitches are unwanted, transient disturbances of short duration, often resembling spikes in a waveform. They are known to occur in a myriad of **switched-mode** systems such as:
- Multi-level power converters
- Systems with friction
- Digital-to-analogue converters (DACs)

In the context of DACs:



# DITHERING AND FILTERING A GLITCH IN OPEN-LOOP [1]

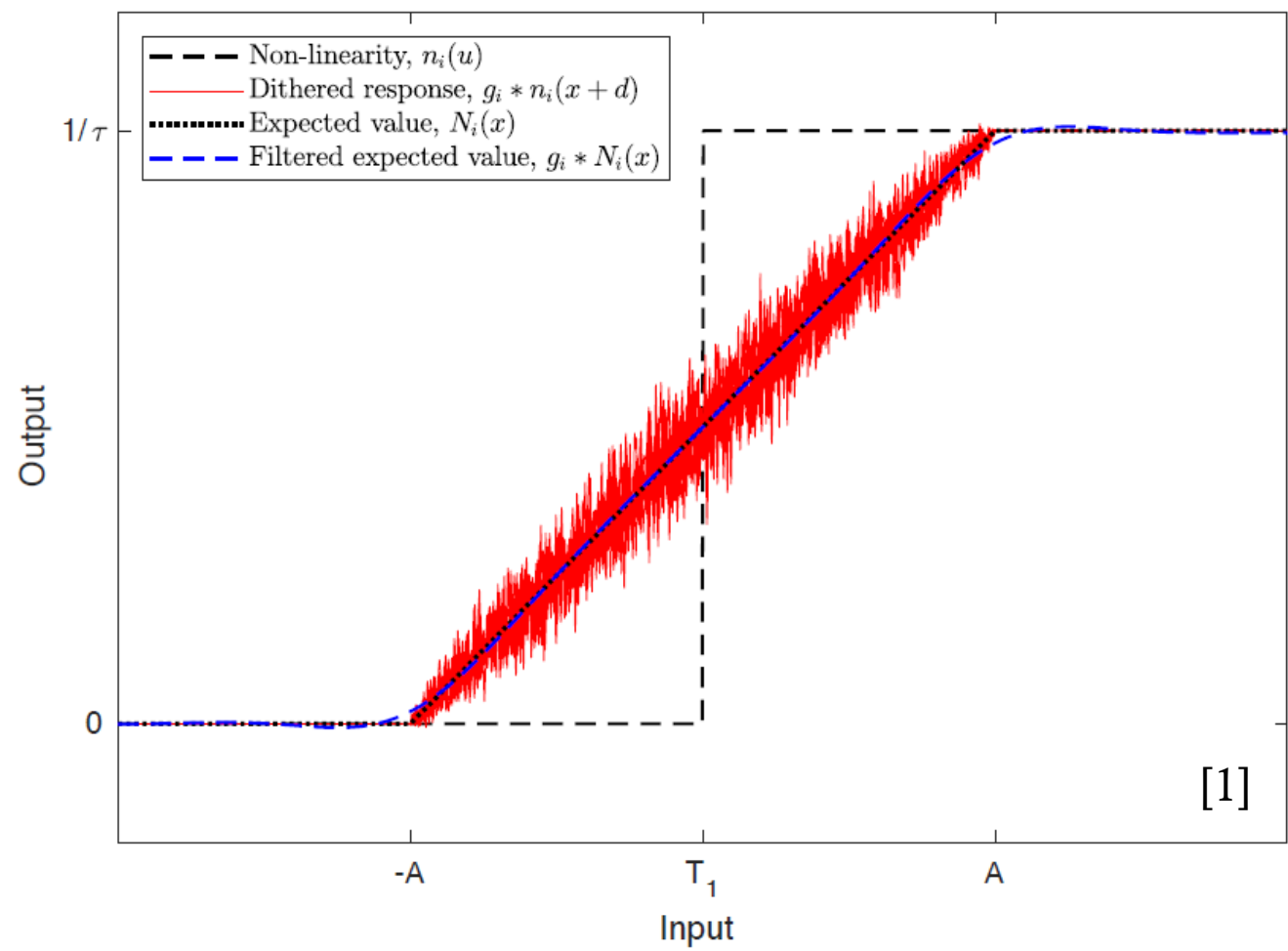
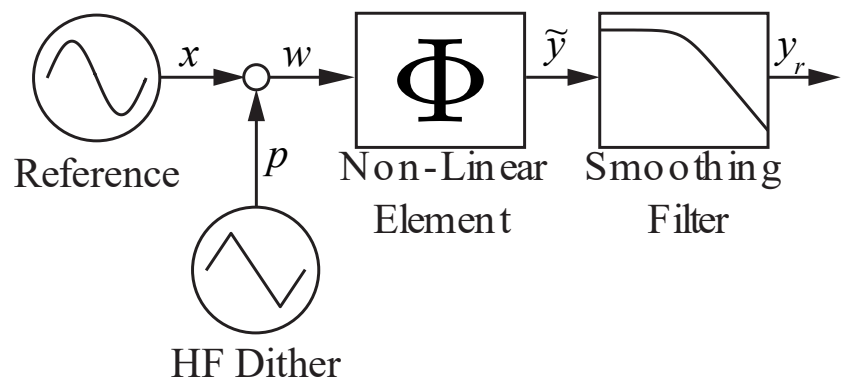
- Smoothed glitch due to periodic dither injection and filtering.





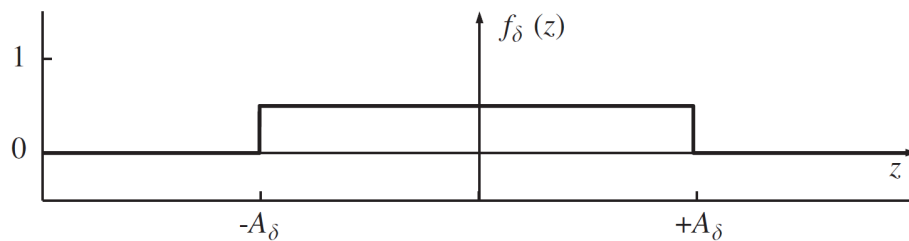
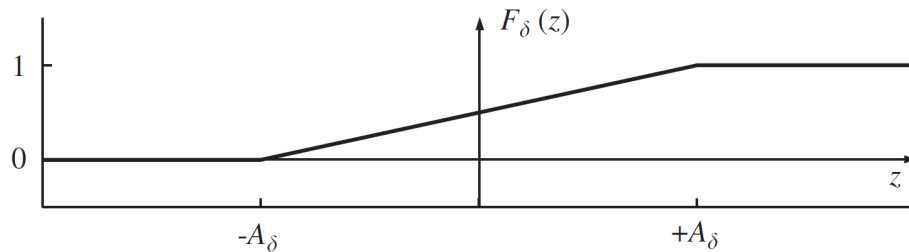
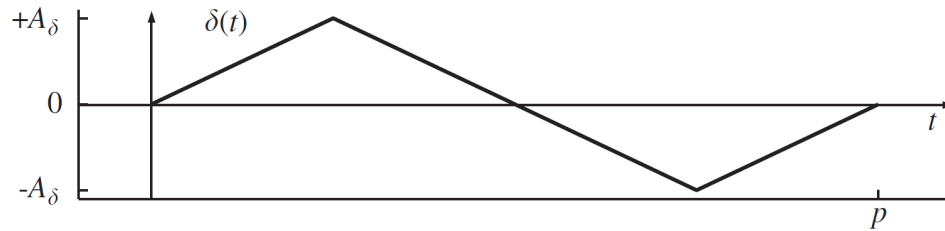
# WHAT IS DITHERING?

- Dithering: is a process by which a form of noise is intentionally applied to a signal in order to randomize the quantization error (e.g. due to intended resolution reduction) [3].



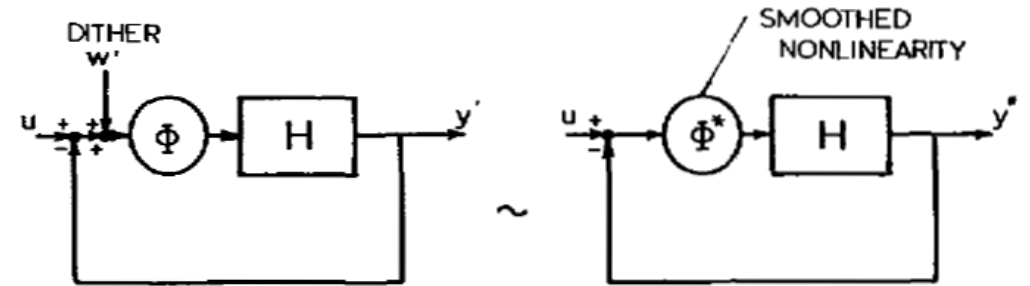
[1]

# DITHER CHARACTERISTICS

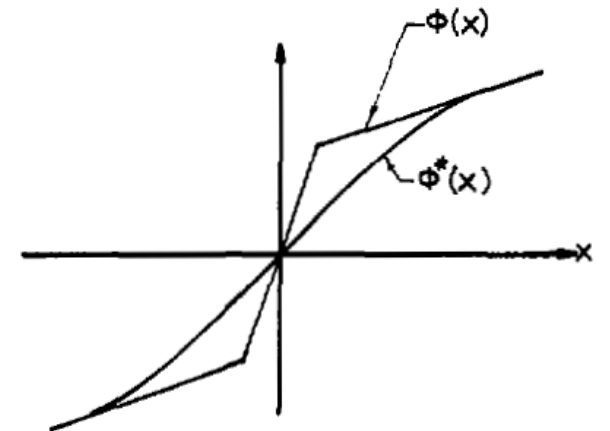


$$\begin{aligned}
 N(z) &\triangleq \int_{\mathbb{R}} n(z + \xi) dF_{\delta}(\xi) \\
 &= \int_{\mathbb{R}} n(z + \xi) f_{\delta}(\xi) d\xi \\
 &= \frac{1}{p} \int_{[0, p)} n(z + \delta(s)) ds
 \end{aligned}$$

[5]



[4]



# A PROPOSED GLITCH MODEL

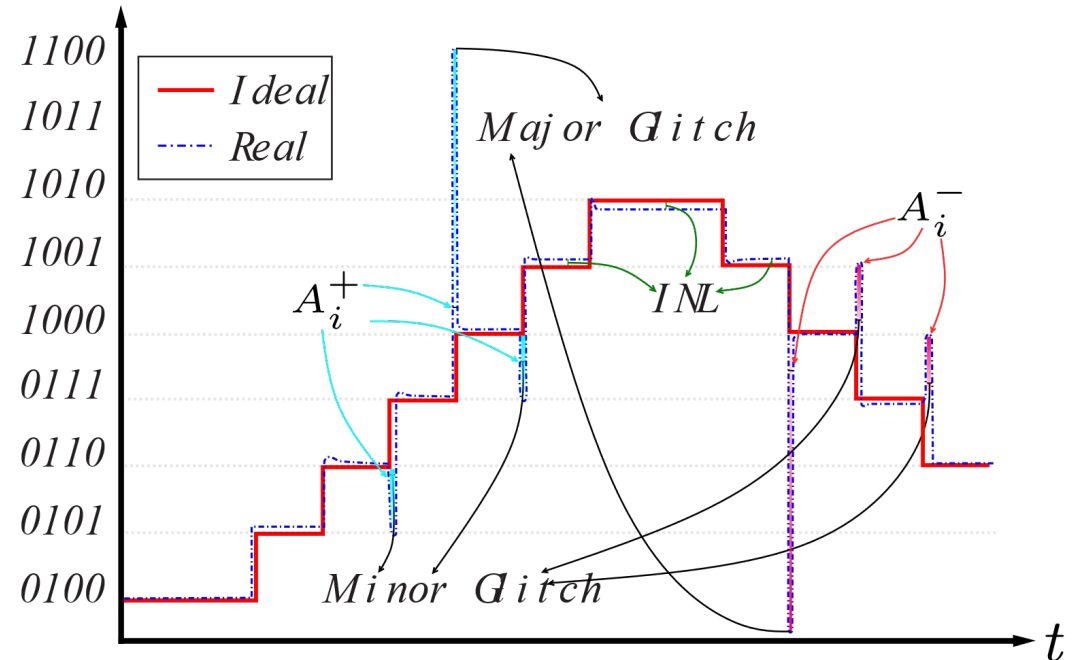
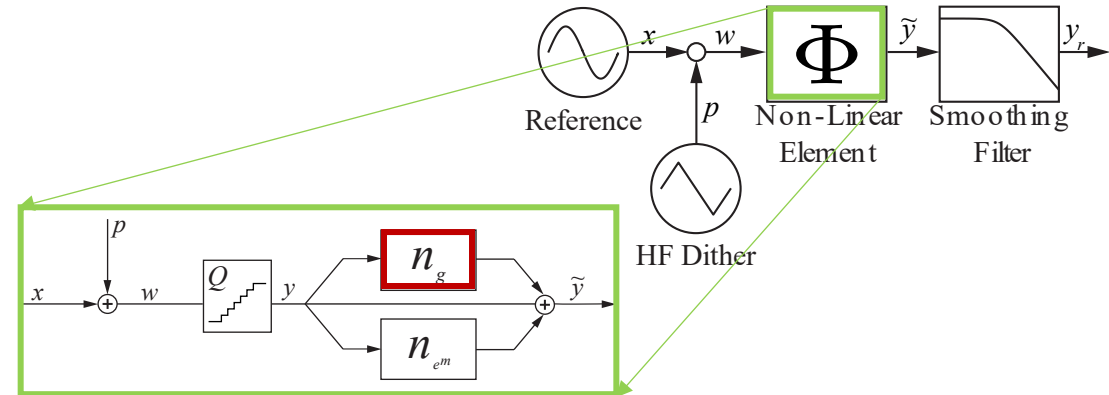
Let  $\tilde{y}(t) = \phi(w(t))$ . we may write  $\phi(w(t)) = n(w(t)) + n_g(w(t))$  with  $n_g(w(t))$  describing the effect of glitches and  $n = \phi - n_g$  accounts for all other effects.

$$n_g(w(t)) \triangleq \sum_{i=1}^{N_T} n_{g_i}(w(t)) \triangleq \sum_{i=1}^{N_T} A_i^\pm(w(t)) \delta(w(t) - T_i).$$

$$A_i^\pm(w(t)) \triangleq \begin{cases} 0 & w(t - \tau) = w(t) \\ A_i^- & w(t - \tau) > w(t) \\ A_i^+ & w(t - \tau) < w(t) \end{cases}$$

Dynamic **Glitch**  
Nonlinearity  $n_g$

- $\delta$  is the Dirac delta function.
- $T_i$  is a threshold value where a glitch is triggered and  $T_i = T_j$  only when  $i = j$ . Thus,  $n_{g_i}$  describes the single glitch related to transition level  $T_i$ .
- $N_T$  is the number of glitch transitions  $T_i$ .
- $A_i^\pm$  is the (input dependent) glitch area. Where  $A_i^+$  ( $A_i^-$ ), indicate net areas of impulse responses for glitches due to references of rising (falling) trend.
- $\tau > 0$  is a finite time-delay. For a DAC,  $\tau$  is limited by the duration between two consecutive input writes.

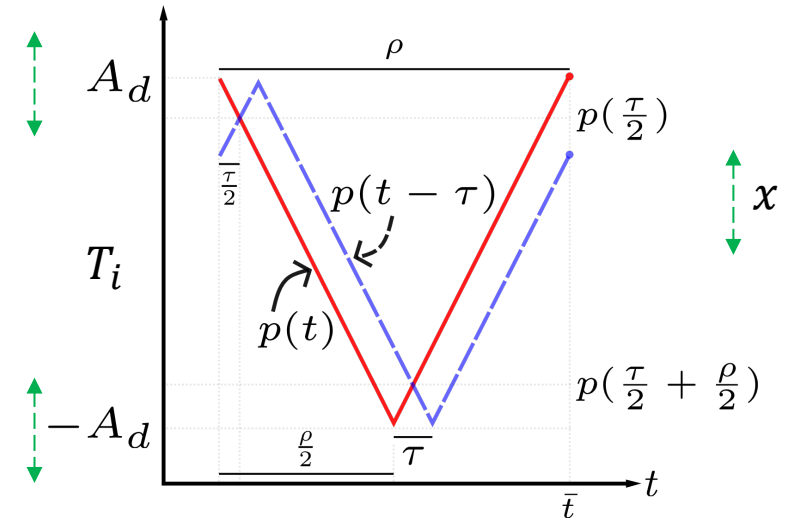


# DITHERING A SINGLE GLITCH

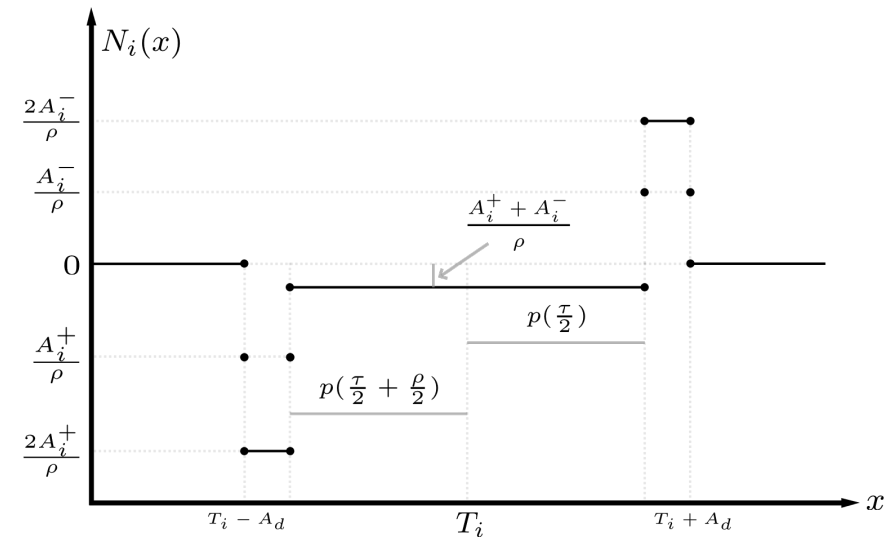
[5]

$$N_i(x) \triangleq \frac{1}{\rho} \int_{[0, \rho)} n_{g_i}(x + p(t)) dt = \frac{1}{\rho} \int_{[0, \rho)} A_i^\pm(x + p(t)) \delta(x + p(t) - T_i) dt \quad x \in \mathbb{R}.$$

- For a triangular wave dither  $p(t)$  of amplitude  $A_d$  and period  $\rho$ :
- Clearly  $N_i(x) \neq 0$  iff  $x + p(t) - T_i = 0$ . Implying that  $x \in [T_i - A_d, T_i + A_d] \triangleq I_x$ .
- To calculate the value of  $N_i(x)$  (for  $x \in I_x$ ) first note that  $A_i^\pm(x + p(t)) = A_i^\pm(p(t))$ .  $A_i^\pm(w(t)) \triangleq \begin{cases} 0 & w(t - \tau) = w(t) \\ A_i^- & w(t - \tau) > w(t) \\ A_i^+ & w(t - \tau) < w(t) \end{cases}$
- Hence, we need to find the **sign** of  $p(t) - p(t - \tau)$  at the **one** or **two** time instances where  $p(t) = T_i - x$ .

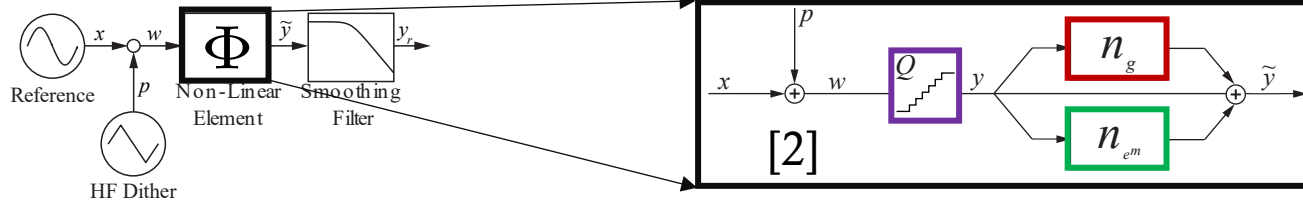


$$N_i(x) = \frac{1}{\rho} \begin{cases} 0 & \text{for } x < T_i - A_d \\ A_i^+ & \text{for } x = T_i - A_d \\ A_i^+ + A_i^+ & \text{for } T_i - A_d < x < T_i - p\left(\frac{\tau}{2}\right) \\ 0 + A_i^+ & \text{for } x = T_i - p\left(\frac{\tau}{2}\right) \\ A_i^- + A_i^+ & \text{for } T_i - p\left(\frac{\tau}{2}\right) < x < T_i - p\left(\frac{\tau}{2} + \frac{\rho}{2}\right) \\ A_i^- + 0 & \text{for } x = T_i - p\left(\frac{\tau}{2} + \frac{\rho}{2}\right) \\ A_i^- + A_i^- & \text{for } T_i + A_d > x > T_i - p\left(\frac{\tau}{2} + \frac{\rho}{2}\right) \\ A_i^- & \text{for } x = T_i + A_d \\ 0 & \text{for } x > T_i + A_d \end{cases}$$



# A VALIDATION MODEL

Comparison to a measured-response-based validation model



Non-linear DAC model accounting for glitched and INL non-linearities for a 16-bit Texas Instruments DAC8544.

Uniform Quantization

$$Q(w) = \delta T(w) = \delta \left\lfloor \frac{w}{\delta} + \frac{1}{2} \right\rfloor$$

$$\delta = \frac{\Delta}{2^B - 1} : \text{LSB}$$

$$\Delta = 5 \text{ to } -5 \text{ V} : \text{FSR}$$

$$n_{em} = \delta \text{INL}(w)$$

$$\text{INL}(w) \triangleq \frac{\tilde{y}(w) - \delta T(w)}{\delta}$$

Element mismatch Nonlinearity [6]

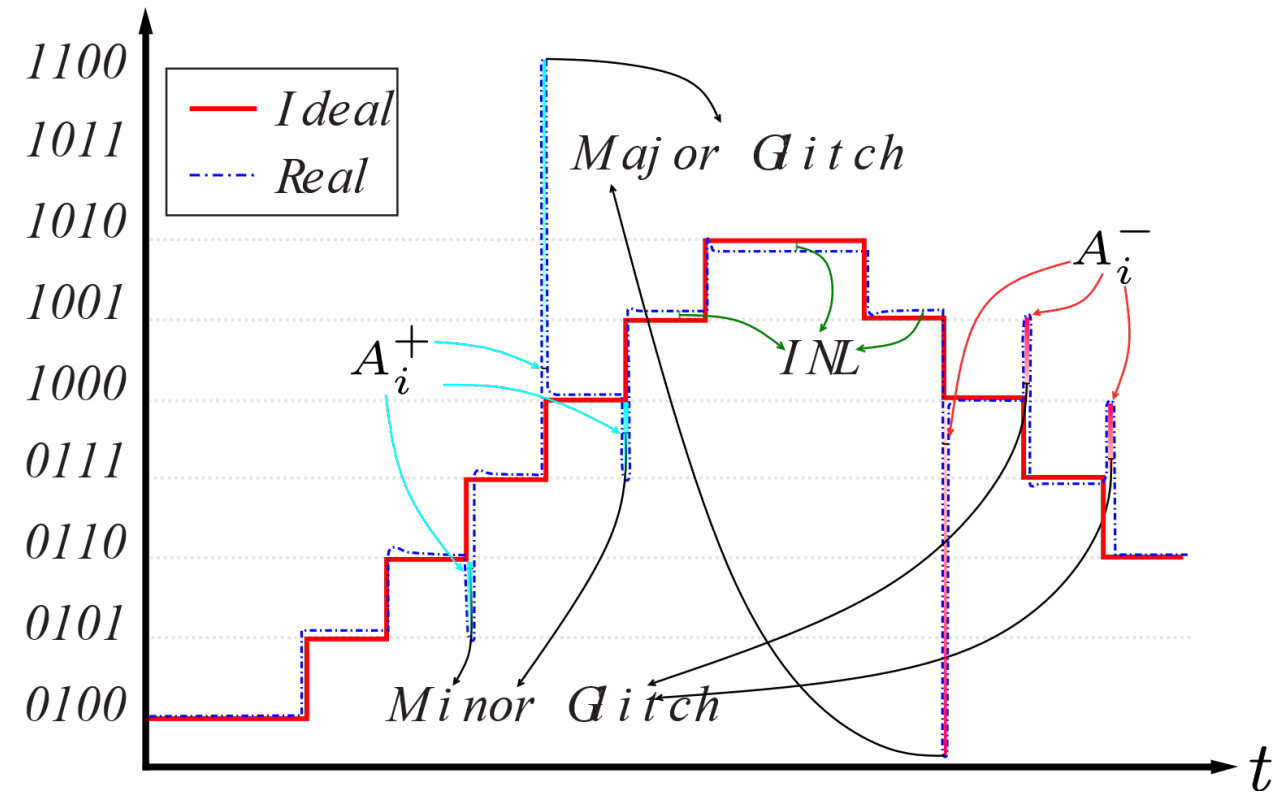
Novel A-/Symmetric **Glitch** Model [1]

Asymmetric ( $T_j; j \in 1 \dots N_{T_s} = 16$ ):  $A_i^+ = -60.6 \text{ nVs}$ ,  $A_i^- = 51.9 \text{ nVs}$

Equidistant:  $\Delta T_s = 4096 \text{ LSB}$

Symmetric ( $T_i; i \in 1 \dots N_{T_s} = 2^{16} - N_{T_s}$ ):  $A_i^+ = -A_i^- = \pm 2.40 \text{ nVs}$

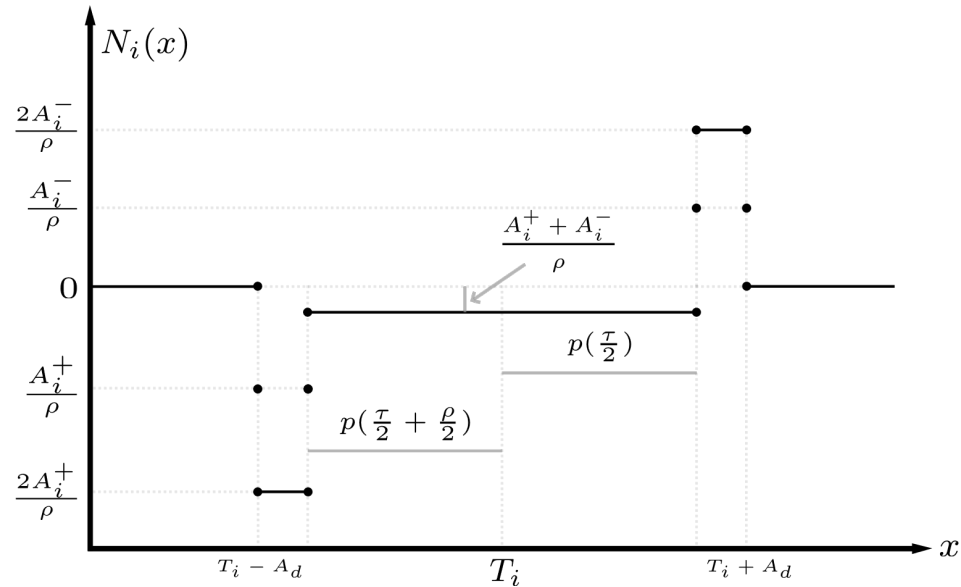
Equidistant:  $\Delta T_s = 1 \text{ LSB}$



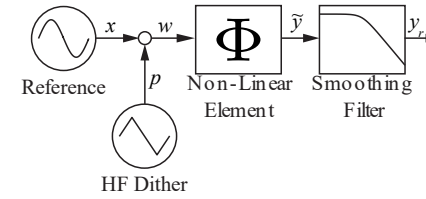


# GLITCH MODEL VERIFICATION

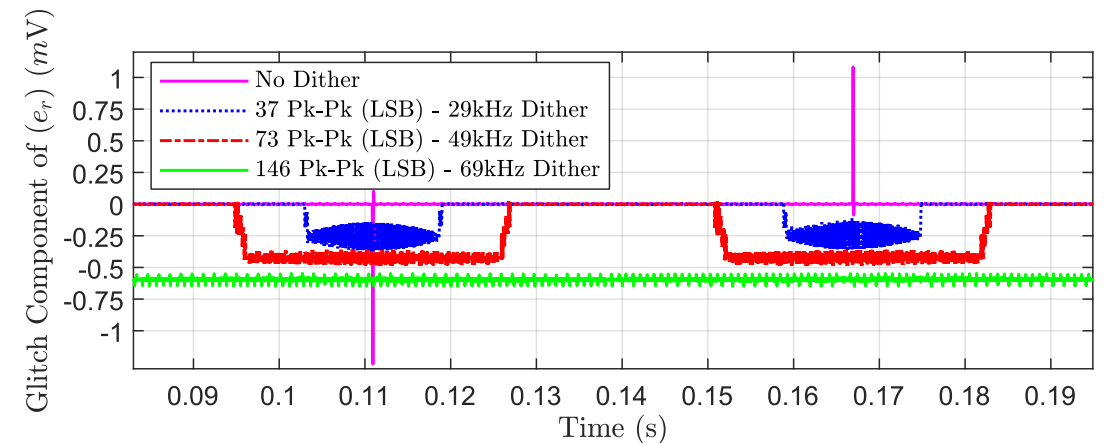
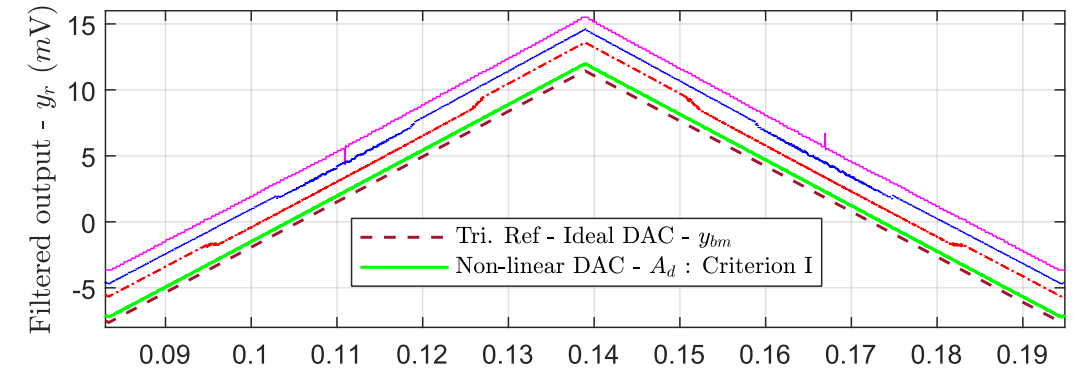
Note that the effect of progressively increasing  $A_d$  is to widen the sector where the averaged response  $N_i$  is a constant equal to  $N_i(x) = (A_i^+ + A_i^-)/\rho = (-60.6 + 51.9)/\rho = -8.6363/\rho$  nV; i.e., -0.25, -0.423, -0.596 mV for  $1/\rho = 29, 49, 69$  kHz respectively.



Note that there seems to be a **sufficiently large** value for  $A_d$  where the averaged response  $N_i(x(t))$  is rendered **constant** for  $t \geq 0$ .



Let  $y_{bm} \triangleq y_r$  when  $\tilde{y} = x$ . (Ideal DAC)  
Then  $e_r \triangleq y_r - y_{bm}$ . (Residual error)



# A CRITERION TO MITIGATE A SINGLE GLITCH

[5]

It is evident that  $n_{g_i}(x(t))$  only depends on  $x(t)$  when  $T_i$  is in the range of  $x(t)$ , that is, when  $T_i \in [X_{min}, X_{max}]$

$$T_i - p\left(\frac{\tau}{2}\right) < x < T_i - p\left(\frac{\tau}{2} + \frac{\rho}{2}\right)$$

$$-A_d\left(1 - \frac{2\tau}{\rho}\right) < T_i - x < A_d\left(1 - \frac{2\tau}{\rho}\right)$$

↓

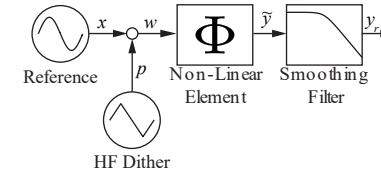
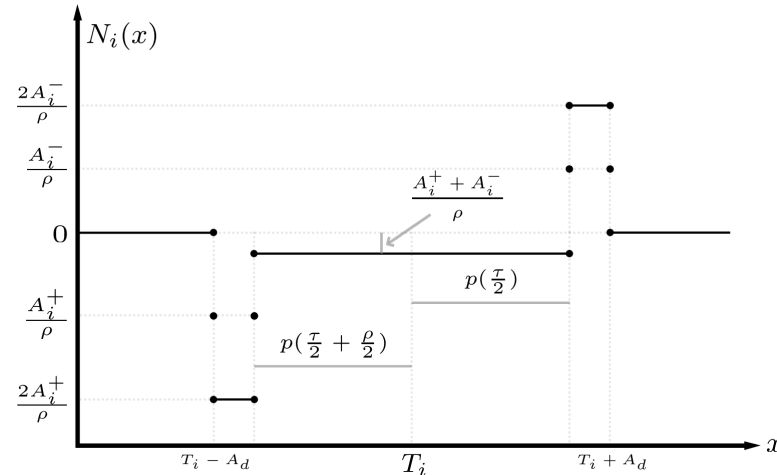
$$N_i(x) = (A_i^- + A_i^+) / \rho \quad \text{for all } A_d > \rho / (\rho - 2\tau) |T_i - x|$$

↓

$A_d$  can be chosen such that  $N_i(x)$  is **constant** for all  $x \in [X_{min}, X_{max}]$  and in turn  $N_i(x(t))$  is **constant** for  $t \geq 0$ .

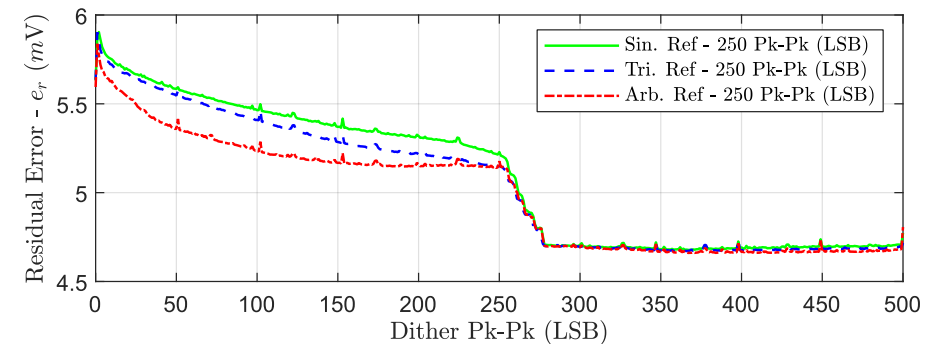
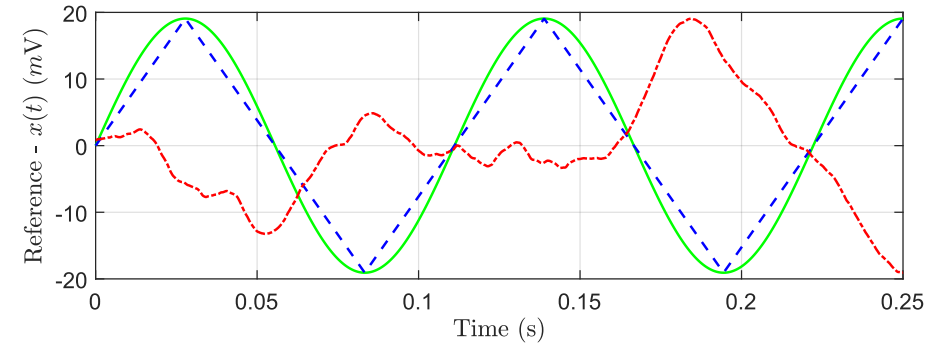
**Criterion I:** 
$$A_d > \left(\frac{\rho}{\rho - 2\tau}\right) \max\{|T_i - X_{min}|, |T_i - X_{max}|\}$$

$$2A_d > 2 \cdot 1.109 \cdot \max(|0 - -125|, |0 - 125|) = 277LSB$$



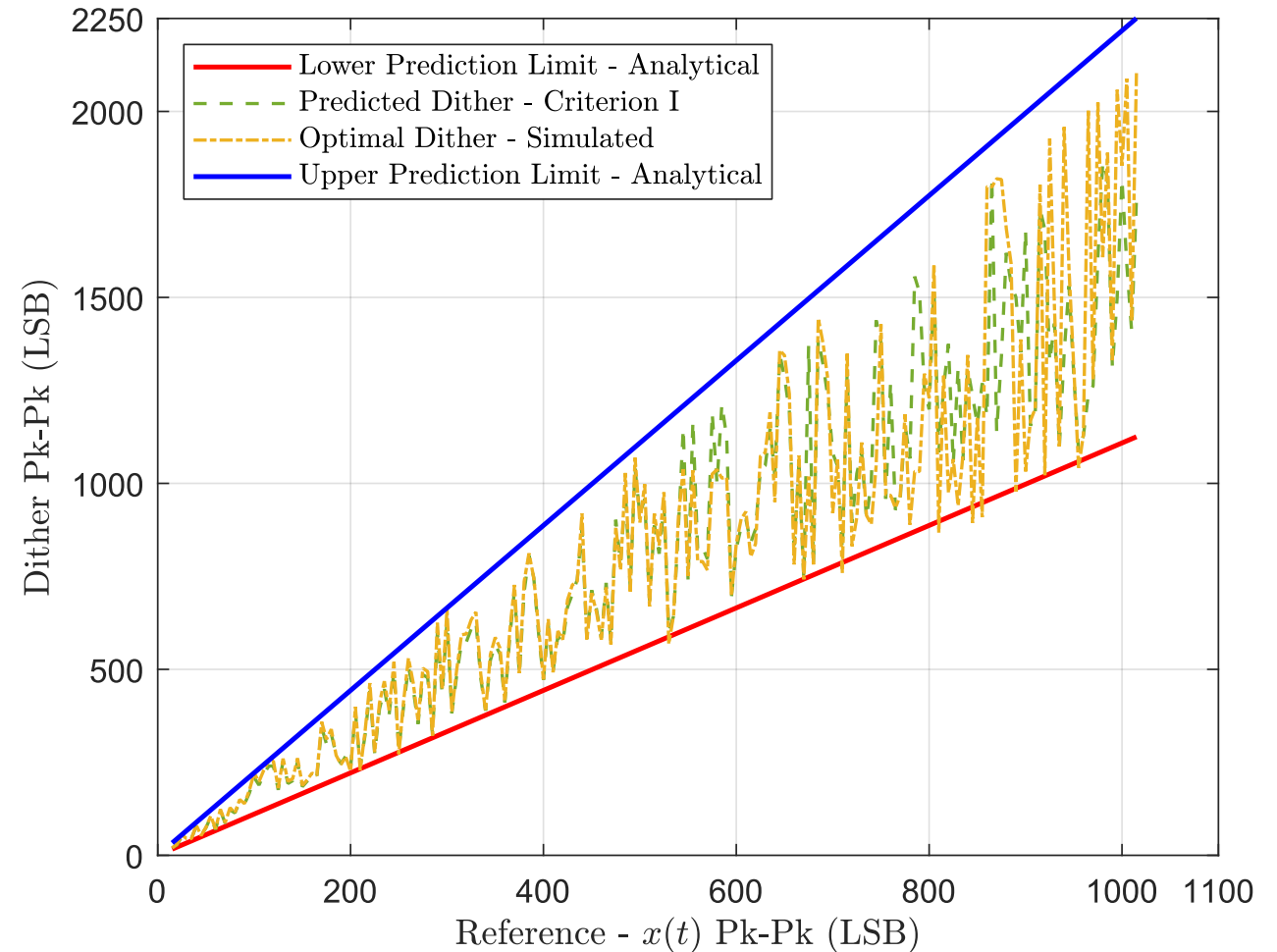
$y_{bm} \triangleq y_r$  when  $\tilde{y} = x$ . (Ideal DAC)  
 $e_r \triangleq y_r - y_{bm}$ . (Residual error)

Various realisations of  $x(t)$  within the range  $x \in [-125, 125]$  LSB: 9~Hz sinusoidal, 9~Hz triangular, and an arbitrary random walk.  
 $T_i = 0$  LSB,  $\frac{1}{\rho} = 49$  kHz,  $\frac{1}{\tau} = 1$  MHz.



# VALIDATING CRITERION I OVER A VARYING RANGE INPUT

- Validating Criterion I at  $n_{g_i}(x(t))$  for an extended range of random walks at various ranges where  $T_i = 0$  LSB is always in the range of  $x(t)$ . By comparing  $A_d$  as predicted in Criterion I due to varying  $X_{min}, X_{max}$ , against  $A_{optimal}$  found when seeking the dither amplitude to render  $N_i(x)$  constant over the range of  $x$  from simulation.
- For all  $T_i$  in the range of  $x(t)$ , the smallest dither amplitude to render  $e_r$  constant is bound between  $\frac{\Delta X}{2}$  (lower prediction limit) and  $\Delta X$  (upper prediction limit)



# A CRITERION TO MITIGATE MULTIPLE EQUIDISTANT GLITCHES

- For  $A_d \geq \frac{\Delta T}{2}$  there will be an overlap between  $N_i(x)$ ,  $N_{i-1}(x)$ , meaning Criterion I renders  $N_g(x)$  constant for all  $x \in [X_{min}, X_{max}]$  when  $x \in [X_{min}, X_{max}] \subseteq [T_i - \left(\frac{(\rho-2\tau)\Delta T}{2\rho}\right), T_i + \left(\frac{(\rho-2\tau)\Delta T}{2\rho}\right)]$ . (**General case limit**)
- An alternative trivial solution would be to take the maximum  $A_d$  from Criterion I over all  $T_j$ :  

$$\max_{j \in \{1,2,3,\dots,N\{T\}\}} \{A_d(j)\}$$
 where  $A_d(j) = \left(\frac{\rho}{\rho-2\tau}\right) \max\{|T_j - X_{min}|, |T_j - X_{max}|\}$ . (**Practical limitations**)
- Note the **special case** for when  $A_{j-1}^\pm = A_j^\pm = A_{j+1}^\pm$ , we have  $N_i(x) = N_i(x + (j-i)\Delta T)$  for  $j > i$ . One can consider merging the side flanks of consecutive single glitches.
- $A_d$  can be chosen such that it stitches neighboring glitches to maximize the range of  $x$  where  $N_g(x)$  is **constant**.

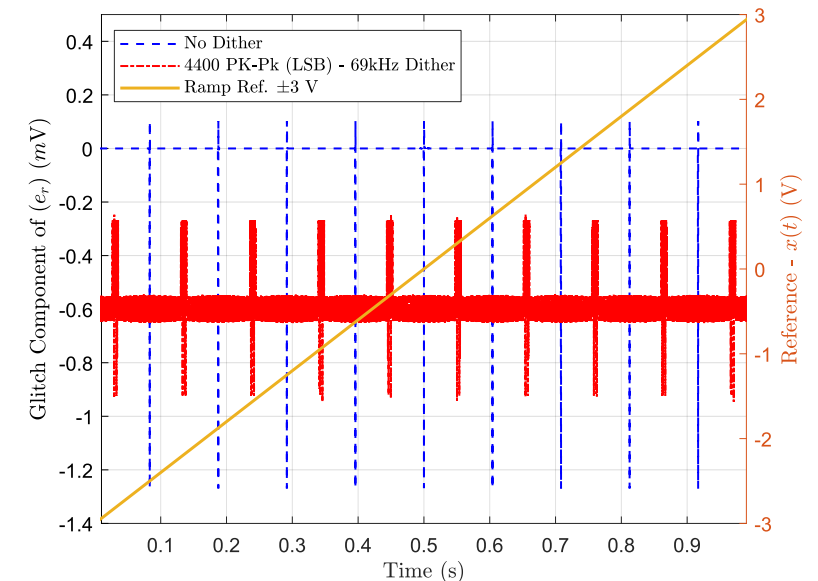
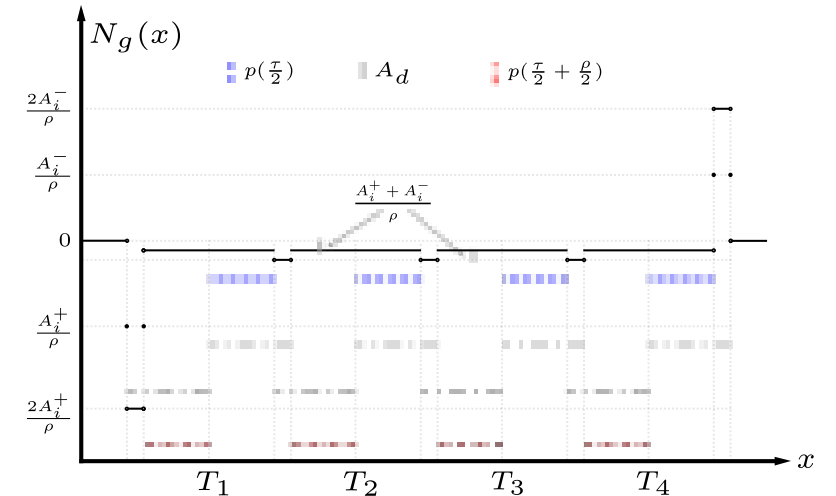
$$p\left(\frac{\tau}{2}\right) + A_d = T_i - T_{i-1} = T_{i+1} - T_i = A_d - p\left(\frac{\tau}{2} + \frac{\rho}{2}\right)$$

$$\Rightarrow \Delta T = 2A_d \left(1 - \frac{\tau}{\rho}\right)$$

**Criterion II:**

$$A_d = \left(\frac{\rho}{\rho - \tau}\right) \frac{\Delta T}{2}$$

$$2A_d = 2 \left(\frac{\rho}{\rho - \tau}\right) \frac{\Delta T_{\tilde{s}}}{2} = 1.07411 \cdot \frac{4096}{2} = 4400LSB$$



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# REFERENCES

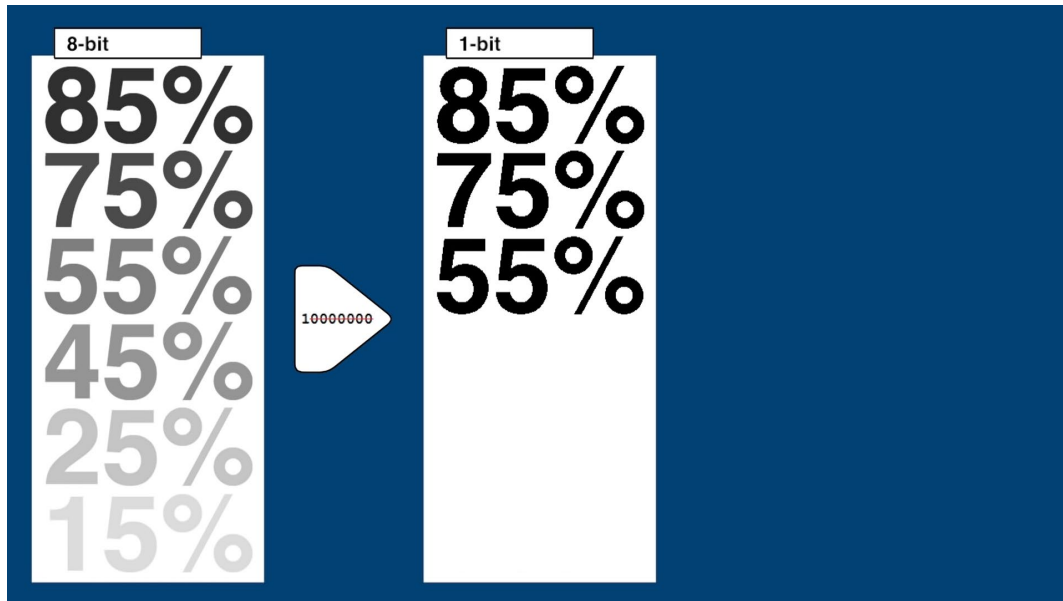
- [1] Eielsen, A. A., Leth, J., Fleming, A. J., Wills, A. G., & Ninness, B. (2020). Large-amplitude Dithering Mitigates Glitches in Digital-to-analogue Converters. *IEEE Transactions on Signal Processing*, 68, 1950-1963.
- [2] Faza, A., Eielsen, A. A., Leth, J. Mitigating Non-linear DAC Glitches Using Dither in Closed-loop Nano-positioning Applications. *In 2023 American Control Conference (ACC)*. (pp. 685-691). IEEE.
- [3] Wannamaker, R. A., Lipshitz, S. P., Vanderkooy, J., & Wright, J. N. (2000). A theory of nonsubtractive dither. *IEEE Transactions on Signal Processing*, 48(2), 499-516.
- [4] Zames, G., & Shneydor, N. (1976). Dither in nonlinear systems. *IEEE Transactions on Automatic Control*, 21(5), 660-667.
- [5] Iannelli, L., Johansson, K. H., Jönsson, U. T., & Vasca, F. (2006). Averaging of nonsmooth systems using dither. *Automatica*, 42(4), 669-676.
- [6] Eielsen, A. A., & Fleming, A. J. (2017). Improving digital-to-analog converter linearity by large high-frequency dithering. *IEEE Transactions on Circuits and Systems I: Regular Papers*, 64(6), 1409-1420.

THANK YOU

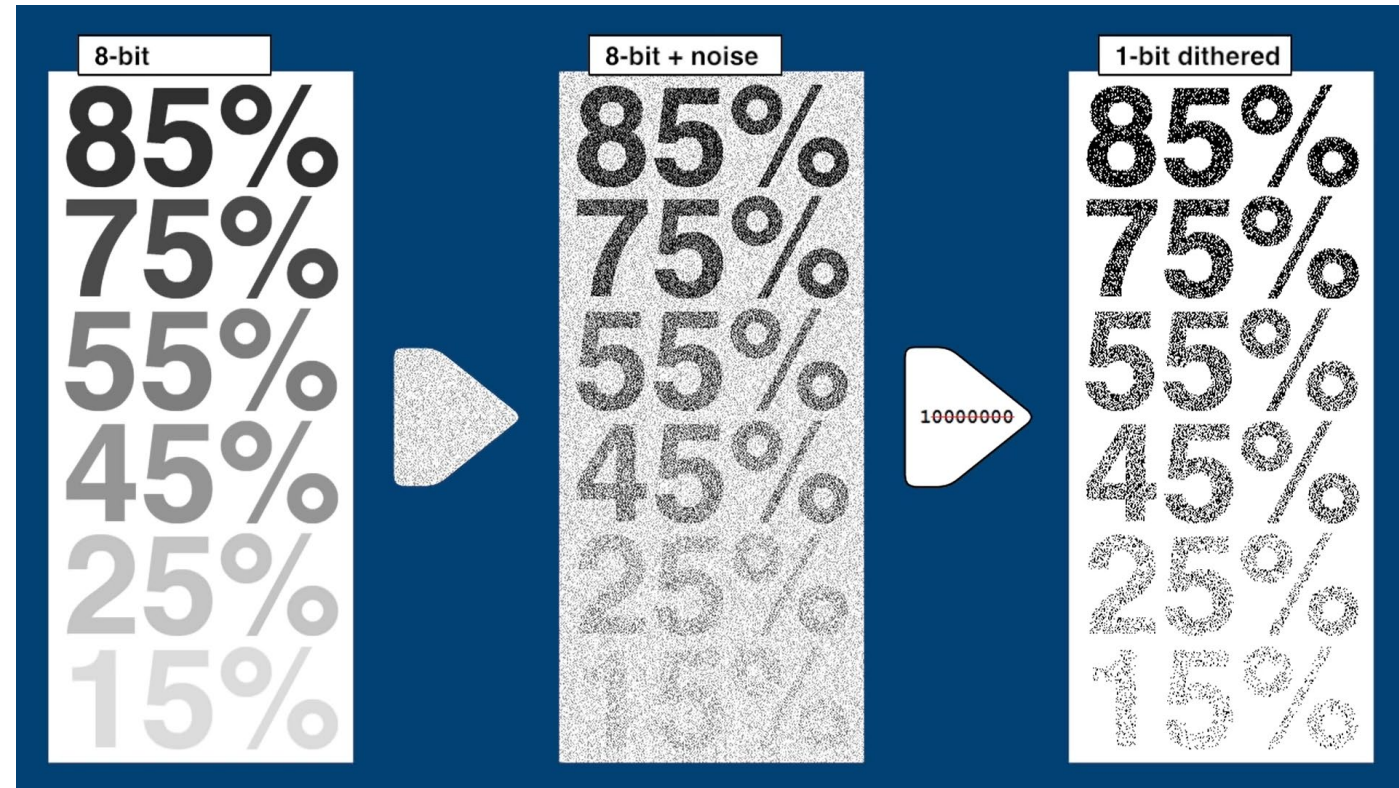
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# DITHERING EXAMPLE

## Ideal Quantization



## Dithered system



# CLOSED-LOOP NANO-POSITIONING SYSTEM

[5]

